Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/817,510	DEPUE ET AL.
Examiner	**Art Unit**
José V. Chen	3637

SEARCHED

Class	Subclass	Date	Examiner
108	44 45 152 42 48	1/18/06	SU
224	400	5/3/06	SU

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Text search Prior Art	1/18/06	SU
	5/3/06	SU
	6/12/06	SU